Form PTO 1449	U.S. DEPARTMENT OF COMMERCE			ATTY DOCKET NO.		SERIAL NO.	
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LIST OF	REFE	RENCES CITED BY AF	PPLICANT	Shunichi IGARASHI			
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OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
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Examiner Kerin Mc Derwit Date of						sidered /	May 6, 2004
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609: Oraw line through citation is not in							
conformance and not considered. Include copy of this form with next communication to applicant.							

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